

SUPPORTING INFORMATION

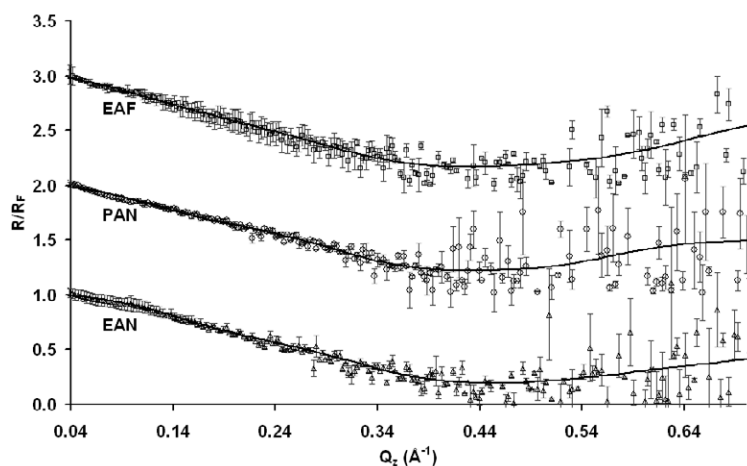


Figure 1: X-ray reflectivity profiles (displayed as R/R_F vs Q_z) for the EAN (Δ), PAN (\circ), and EAF (\square) - air interface. The solid lines represent the modeled x-ray reflectivities fit to each set of data using the slices approach. The PAN and EAF data have been vertically offset for clarity.

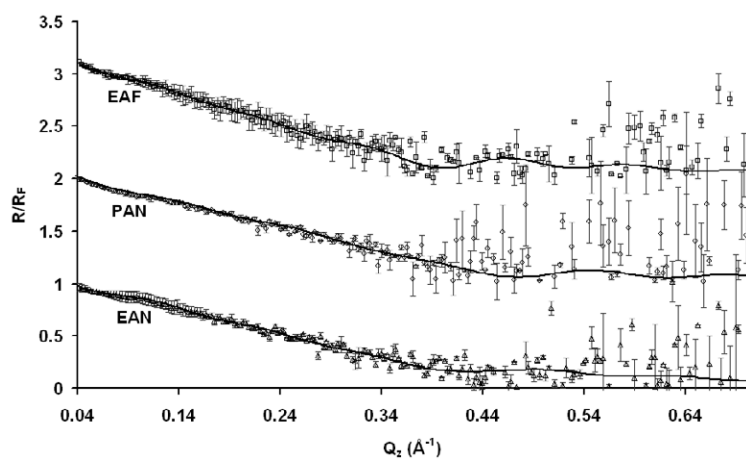


Figure 2: X-ray reflectivity profiles (displayed as R/R_F vs Q_z) for the EAN (Δ), PAN (\circ), and EAF (\square) - air interface. The solid lines represent the modeled x-ray reflectivities fit to each set of data using the Chebyshev approach. The EAN and EAF data have been vertically offset for clarity.

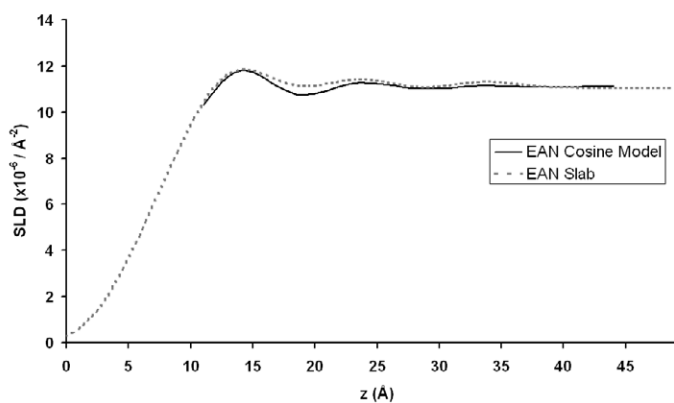


Figure 3: SLD profiles for EAN using the slab model and cosine model

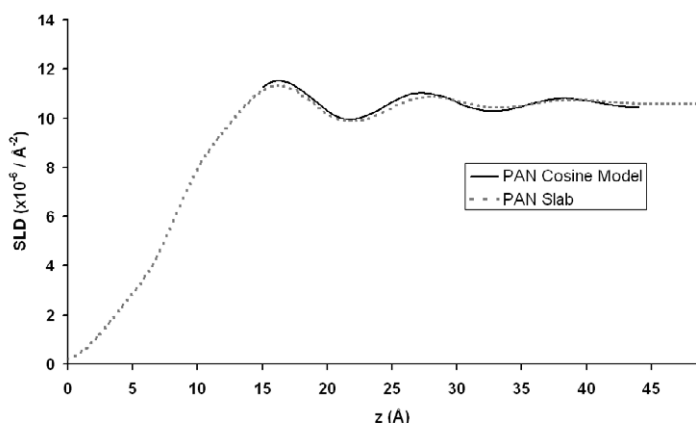


Figure 4: SLD profiles for PAN using the slab model and cosine model

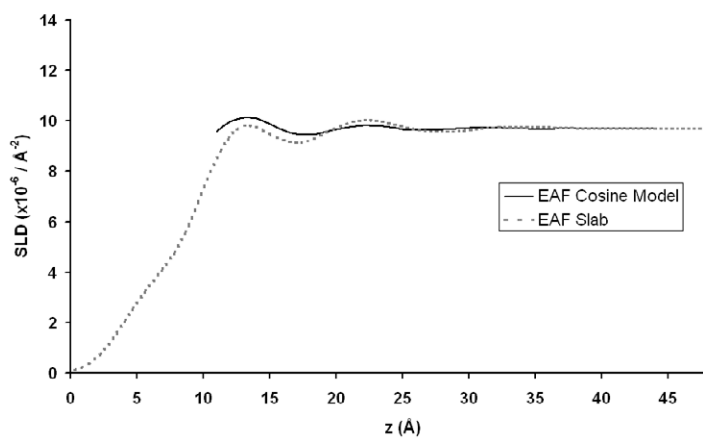


Figure 5: SLD profiles for EAF using the slab model and cosine model